

DIN EN 12698-2:2007-06 (E)

Chemical analysis of nitride bonded silicon carbide refractories - Part 2: XRD methods

Contents	Page
Foreword	3
1 Scope	4
2 Normative references	4
3 Definitions	4
4 Apparatus	4
5 Sampling	5
6 Procedure	5
6.1 Sample preparation	5
6.2 Measuring parameters	5
6.3 Qualitative analysis	5
6.4 Quantitative analysis	6
7 Precision	10
7.1 Repeatability	10
7.2 Reproducibility	10
8 Test report	10
Annex A (normative) X-ray diffraction data for the determination of 'SiAlON content	11
A.1 General	11
A.2 Example of calculation of z-value for 'SiAlON	12
Bibliography	13